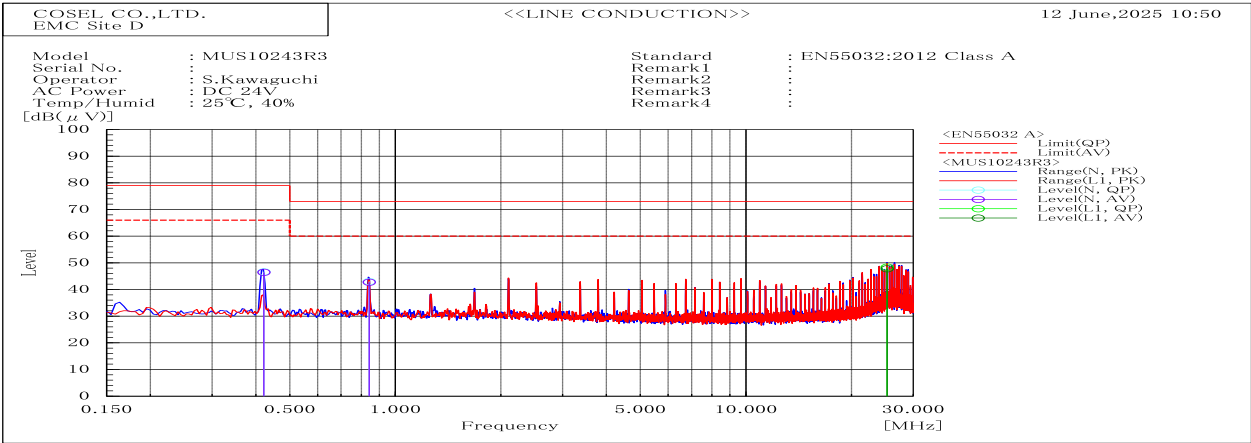
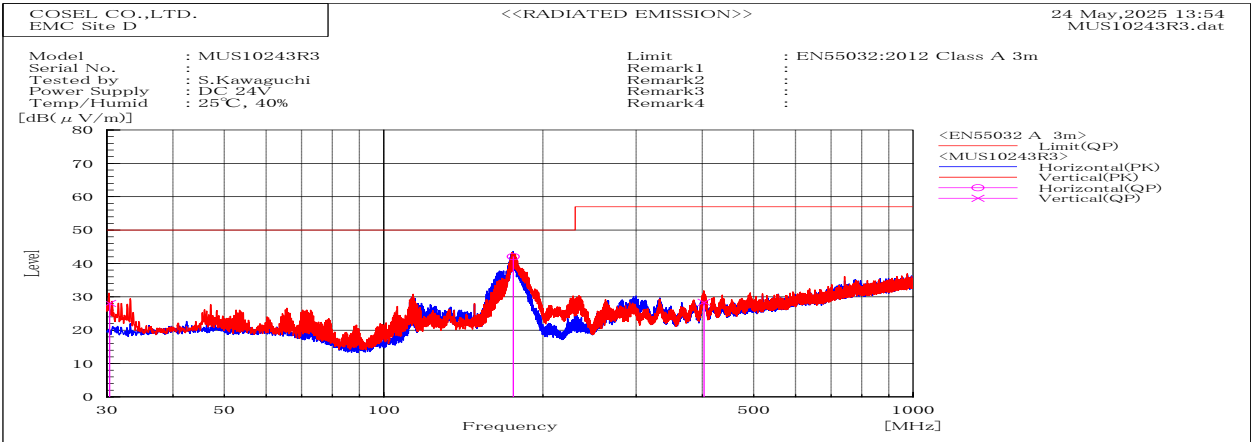


DATA SHEET		Date	12-Jun-25
Model	MUS10243R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



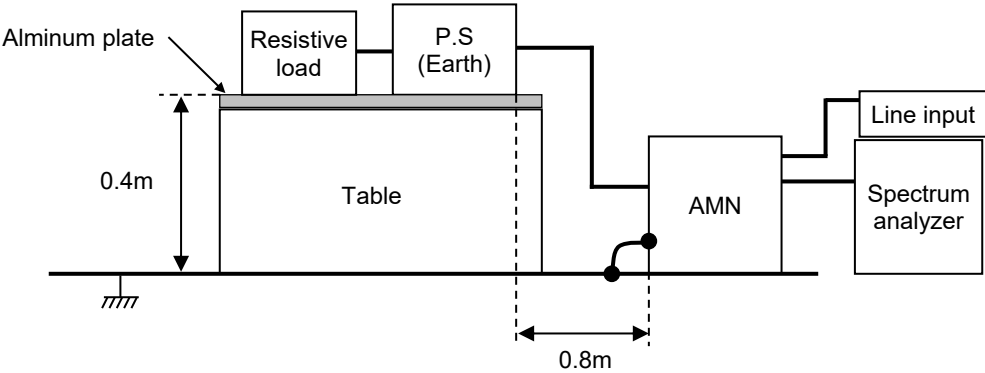
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
25.285	L1	48.4	47.8	73	60	24.6	12.2	Pass	
0.422	N	46.6	46.4	79	66	32.4	19.6	Pass	
0.843	N	43	42.7	73	60	30	17.3	Pass	



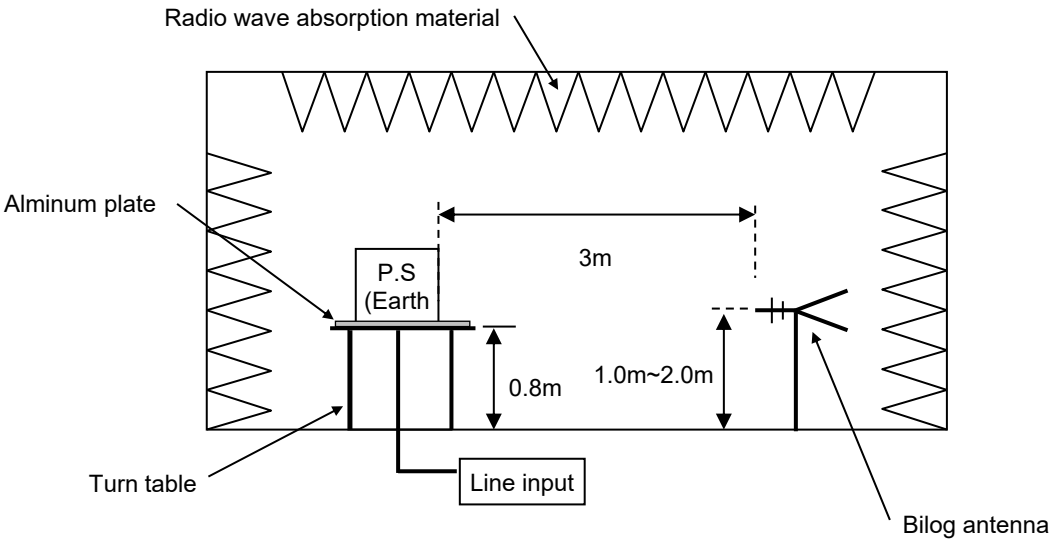
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
175.738	H	Stable	42.1	50	7.9	Pass	200	258	
30.354	V	Stable	28	50	22	Pass	101.5	0	
402.901	V	Stable	28.3	57	28.7	Pass	130.5	243.3	

DATA SHEET		Date	12-Jun-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

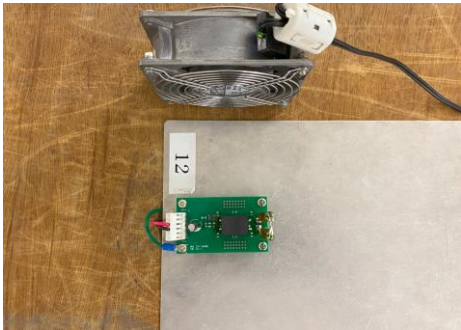
Test : EMI  
 Model Name: MUS10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

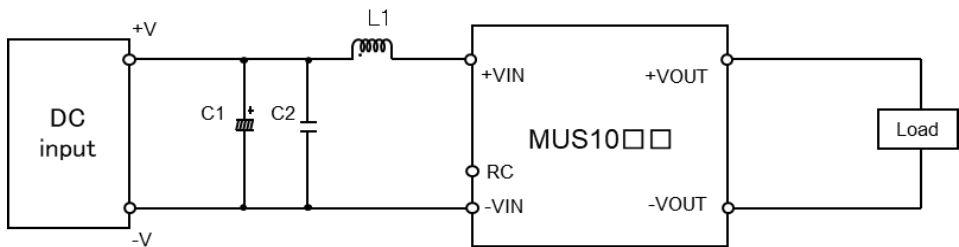


Fig.1 MUS10□□ Testing circuitry

C1 :	MUS1005□	25V 1500 $\mu$ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUS1012□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS1024□	—	
	MUS1048□	—	
C2 :	MUS1005□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1012□	25V 10 $\mu$ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS1024□	50V 4.7 $\mu$ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1048□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1005□	5000mA 2.2 $\mu$ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS1012□	3500mA 4.7 $\mu$ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUS1024□	1600mA 22 $\mu$ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1048□	1100mA 47 $\mu$ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)